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Report No.: SZEM180500437005

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RF Exposure Evaluation Report

Application No.: SZEM1805004370RG **Applicant:** Fibocom Wireless Inc.

Address of Applicant 5/F, Tower A, Technology Building II, 1057 Nanhai Avenue, Shenzhen,

China

Manufacturer: Fibocom Wireless Inc.

Address of Manufacturer 5/F, Tower A, Technology Building II, 1057 Nanhai Avenue, Shenzhen,

China

Factory: DongGuan Huabel Electronic Technology Co.,Ltd

Address of Factory:

No.9,Industrial Northern Road,National High Tech Industrial Development

Zone, SongShan Lake DongGuan city, GuangDong provice P.R.China

Product Name: LTE Module
Model No.(EUT): L860-GL
Trade Mark: Fibocom
FCC ID: ZMOL860GL

Standards: 47 CFR Part 2

47 CFR Part 22 subpart H 47 CFR Part 24 subpart E 47 CFR Part 27 subpart C 47 CFR Part 90 subpart R 47 CFR Part 90 subpart S

Date of Receipt: 2018-06-12

Date of Test: 2018-06-15 to 2018-09-03

Date of Issue: 2018-09-03

Test Result: PASS*

Authorized Signature:

Derele yang

Derek Yang Wireless Laboratory Manager

The manufacturer should ensure that all products in series production are in conformity with the product sample detailed in this report. If the product in this report is used in any configuration other than that detailed in the report, the manufacturer must ensure the new system complies with all relevant standards. Any mention of SGS International Electrical Approvals or testing done by SGS International Electrical Approvals in connection with, distribution or use of the product described in this report must be approved by SGS International Electrical Approvals in writing.

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^{*} In the configuration tested, the EUT complied with the standards specified above.



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1 Version

Revision Record									
Version	Chapter	Date	Modifier	Remark					
01		2018-09-03		Original					

Authorized for issue by:		
	Mike Hu/Project Engineer	2018-09-03
	David Chen	2018-09-03
	David Chen /Reviewer	_



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2 General Information

2.1 Client Information

Applicant:	Fibocom Wireless Inc.				
Address of Applicant:	5/F, Tower A, Technology Building II, 1057 Nanhai Avenue, Shenzhen, China				
Manufacturer:	Fibocom Wireless Inc.				
Address of Manufacturer:	5/F, Tower A, Technology Building II, 1057 Nanhai Avenue, Shenzhen, China				
Factory:	DongGuan Huabel Electronic Technology Co.,Ltd				
Address of Factory:	No.9,Industrial Northern Road,National High Tech Industrial Development Zone, SongShan Lake DongGuan city, GuangDong provice P.R.China				

2.2 General Description of EUT

Product Name:	LTE Module
	LIE Module
Model No.:	L860-GL
Trade Mark:	Fibocom
Hardware Version	V1.2
Software Version	18600.5003.00.17.00.02
Sample Type:	LTE Module
Antenna Type:	Dipole
Antenna Gain:	WCDMA BAND II: 4dBi; WCDMA BAND V: 4dBi; WCDMA BAND V: 3dBi; LTE BAND 2: 4dBi; LTE BAND 4: 4dBi; LTE BAND 5:3dBi; LTE BAND 7: 4dBi; LTE BAND 12: 3dBi; LTE BAND 13: 2dBi; LTE BAND 14: 2dBi; LTE BAND 14: 2dBi; LTE BAND 25: 4dBi; LTE BAND 25: 4dBi; LTE BAND 26: 3dBi; LTE BAND 30: 1dBi; LTE BAND 38: 4dBi; LTE BAND 41: 3dBi; LTE BAND 66: 4dBi;



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2.3 Test Mode

Test Mode	Test Modes Description
UMTS/TM1	UMTS system, WCDMA, QPSK modulation
UMTS/TM2	UMTS system, WCDMA, 16QAM modulation
LTE/TM1	LTE system, QPSK modulation
LTE/TM2	LTE system, 16QAM modulation
LTE/TM3	LTE system, 64QAM modulation

NOTE: The test mode(s) are selected according to relevant radio technology specifications.

2.4 Test Location

All tests were performed at:

SGS-CSTC Standards Technical Services Co., Ltd. Shenzhen Branch

No. 1 Workshop, M-10, Middle section, Science & Technology Park, Shenzhen, Guangdong, China 518057

Telephone: +86 (0) 755 2601 2053 Fax: +86 (0) 755 2671 0594

No tests were sub-contracted.

2.5 Test Facility

The test facility is recognized, certified, or accredited by the following organizations:

CNAS (No. CNAS L2929)

CNAS has accredited SGS-CSTC Standards Technical Services Co., Ltd. Shenzhen Branch EMC

Lab to ISO/IEC 17025:2005 General Requirements for the Competence of Testing and Calibration Laboratories (CNAS-CL01 Accreditation Criteria for the Competence of Testing and Calibration Laboratories) for the competence in the field of testing.

A2LA (Certificate No. 3816.01)

SGS-CSTC Standards Technical Services Co., Ltd., Shenzhen EMC Laboratory is accredited by the American Association for Laboratory Accreditation(A2LA). Certificate No. 3816.01.

VCCI

The 3m Fully-anechoic chamber for above 1GHz, 10m Semi-anechoic chamber for below 1GHz, Shielded Room for Mains Port Conducted Interference Measurement and Telecommunication Port Conducted Interference Measurement of SGS-CSTC Standards Technical Services Co., Ltd. have been registered in accordance with the Regulations for Voluntary Control Measures with Registration No.: G-20026, R-14188, C-12383 and T-11153 respectively.

• FCC -Designation Number: CN1178

SGS-CSTC Standards Technical Services Co., Ltd., Shenzhen EMC Laboratory has been recognized as an accredited testing laboratory.

Designation Number: CN1178. Test Firm Registration Number: 406779.

• Industry Canada (IC)

Two 3m Semi-anechoic chambers and the 10m Semi-anechoic chamber of SGS-CSTC Standards Technical Services Co., Ltd. Shenzhen Branch EMC Lab have been registered by Certification and Engineering Bureau of Industry Canada for radio equipment testing with Registration No.: 4620C-1, 4620C-2, 4620C-3.

2.6 Deviation from Standards

None.

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2.7 Abnormalities from Standard Conditions

None.

2.8 Other Information Requested by the Customer

None.



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3 RF Exposure Evaluation

3.1 RF Exposure Compliance Requirement

3.1.1 Limits

Frequency range (MHz)	Electric field strength (V/m)	Magnetic field strength (A/m)	Power density (mW/cm²)	Averaging time (minutes)					
(A) Limits for Occupational/Controlled Exposures									
0.3-3.0 614 1.63 *(100) 6									
3.0-30	1842/f	4.89/f	*(900/f²)	6					
30-300	61.4	0.163	1.0	6					
300-1500	/	/	f/300	6					
1500-100,000	/	1	6						
(B) Limits for General Population/Uncontrolled Exposure									
0.3-1.34	614	1.63	*(100)	30					
1.34-30	1.34-30 824/f		*(180/f²)	30					
30-300	27.5	0.073	0.2	30					
300-1500	/	/	f/1500	30					
1500-100,000	/	1	1.0	30					

F=frequency in MHz

*=Plane-wave equivalent power density

RF exposure compliance will need to be determined with respect to 1.1307(c) and (d) of the FCC rules. The emissions should be within the limits at 300kHz in Table 1 of 1.1310(use the 300kHz limits for 150kHz:614V/m,1.63A/m).

Friis Formula

Friis transmission formula: Pd = (Pout*G)/(4* Pi * R 2)

Where

Pd = power density in mW/cm2

Pout = output power to antenna in mW

G = gain of antenna in linear scale

Pi = 3.1416

R = distance between observation point and center of the radiator in cm

Pd id the limit of MPE, 1 mW/cm2 . If we know the maximum gain of the antenna and the total power input to the antenna, through the calculation, we will know the distance r where the MPE limit is reached.

3.1.2 Test Procedure

Software provided by client enabled the EUT to transmit data at lowest, middle and highest channel individually.



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3.1.3 EUT RF Exposure Evaluation

Antenna Gain: The maximum Gain measured in fully anechoic chamber is 2.0 / 2.0 in linear scale. Output Power Into Antenna & RF Exposure Evaluation Distance:

Operating Band	Frequen cy (MHz)	Gain (dBi)	Max Conducted Average Output Power (dBm)	Output Power to Antenna (dBm)	EIRP(ERP) Limit (dBm)	Output Power to Antenna (mw)	Power Density at R = 20 cm (mW/cm2)	Limit (W/m2)	Gain according to EIRP (dBi)	Gain according to Pd (dBi)	Max Gain Allowed (dBi)	conclusion
WCDMA B2	1852.4	4.00	24.50	28.50	33.00	281.8383	0.1408	1.0000	8.50	12.51	8.50	Pass
WCDMA B4	1712.4	4.00	24.50	28.50	30.00	281.8383	0.1408	1.0000	5.50	12.51	5.50	Pass
WCDMA B5	826.4	3.00	24.50	25.35	38.45	281.8383	0.1119	0.5509	16.10	9.92	9.92	Pass
LTE B2	1850.7	4.00	24.00	28.00	33.00	251.1886	0.1255	1.0000	9.00	13.01	9.00	Pass
LTE B4	1710.7	4.00	24.00	28.00	30.00	251.1886	0.1255	1.0000	6.00	13.01	6.00	Pass
LTE B5	824.7	3.00	25.00	25.85	38.45	316.2278	0.1255	0.5498	15.60	9.41	9.41	Pass
LTE B7	2502.5	4.00	24.00	28.00	33.00	251.1886	0.1255	1.0000	9.00	13.01	9.00	Pass
LTE B12	699.7	3.00	24.00	24.85	34.77	251.1886	0.0997	0.4665	12.92	9.70	9.70	Pass
LTE B13	779.5	2.00	24.00	23.85	34.77	251.1886	0.0792	0.5197	12.92	10.16	10.16	Pass
LTE B14	790.5	2.00	24.00	23.85	34.77	251.1886	0.0792	0.5270	12.92	10.23	10.23	Pass
LTE B17	706.5	3.00	24.00	24.85	34.77	251.1886	0.0997	0.4710	12.92	9.74	9.74	Pass
LTE B25	1850.7	4.00	24.00	28.00	33.00	251.1886	0.1255	1.0000	9.00	13.01	9.00	Pass
LTE B26(814-824)	814.7	3.00	25.00	25.85	50.00	316.2278	0.1255	0.5431	27.15	9.36	9.36	Pass
LTE B26(824-849)	824.7	3.00	25.00	25.85	38.45	316.2278	0.1255	0.5498	15.60	9.41	9.41	Pass
LTE B30	2307.5	1.00	23.00	24.00	24.00	199.5262	0.0500	1.0000	1.00	14.01	1.00	Pass
LTE B38	2572.5	4.00	24.00	28.00	33.00	251.1886	0.1255	1.0000	9.00	13.01	9.00	Pass
LTE B41	2498.5	4.00	27.50	31.50	33.00	562.3413	0.2810	1.0000	5.50	9.51	5.50	Pass
LTE B66	1710.7	4.00	24.00	28.00	30.00	251.1886	0.1255	1.0000	6.00	13.01	6.00	Pass

Note: Refer to report No. SZEM180500437001 for EUT test Max Conducted Output Power value.